Power MOSFET -10 Amps, -20 Volts

P-Channel Enhancement-Mode Single SOIC-8 Package

Features

- Ultra Low R_{DS(on)}
- Higher Efficiency Extending Battery Life
- Logic Level Gate Drive
- Miniature SOIC-8 Surface Mount Package
- Diode Exhibits High Speed, Soft Recovery
- Avalanche Energy Specified
- SOIC-8 Mounting Information Provided
- Pb-Free Package is Available

Applications

• Power Management in Portable and Battery-Powered Products, i.e.: Cellular and Cordless Telephones and PCMCIA Cards

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	-20	Vdc
Gate-to-Source Voltage - Continuous	V_{GS}	±12	Vdc
Thermal Resistance – Junction-to-Ambient (Note 1) Total Power Dissipation @ T _A = 25°C Continuous Drain Current @ 25°C Continuous Drain Current @ 70°C Maximum Operating Power Dissipation Maximum Operating Drain Current Pulsed Drain Current (Note 3)	R _{θJA} P _D I _D I _D I _D I _D I _D I _D	50 2.5 -10 -8.0 0.6 -5.5 -50	°C/W W A A W A
Thermal Resistance – Junction-to-Ambient (Note 2) Total Power Dissipation @ T _A = 25°C Continuous Drain Current @ 25°C Continuous Drain Current @ 70°C Maximum Operating Power Dissipation Maximum Operating Drain Current Pulsed Drain Current (Note 3)	R _{θJA} P _D I _D I _D I _D I _{DM}	80 1.6 -8.8 -6.4 0.4 -4.5 -44	°C/W W A A W A
Operating and Storage Temperature Range	T _J , T _{stg}	-55 to +150	°C
Single Pulse Drain–to–Source Avalanche Energy – Starting T_J = 25°C (V_{DD} = -20 Vdc, V_{GS} = -4.5 Vdc, Peak I_L = 5.0 Apk, L = 40 mH, R_G = 25 Ω)	E _{AS}	500	mJ
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds	TL	260	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

- 1. Mounted onto a 2" square FR-4 Board (1 in sq, Cu 0.06" thick single sided), t = 10 seconds.
- Mounted onto a 2" square FR-4 Board (1 in sq, Cu 0.06" thick single sided), t = steady state.
- 3. Pulse Test: Pulse Width < 300 μs, Duty Cycle < 2%.

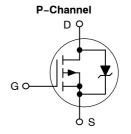


ON Semiconductor®

http://onsemi.com

-10 AMPERES -20 VOLTS

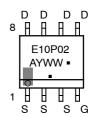
14 m Ω @ V_{GS} = -4.5 V



MARKING DIAGRAM & PIN ASSIGNMENT



SOIC-8 CASE 751 STYLE 12



E10P02 = Specific Device Code A = Assembly Location

= Year

W = Work Week = Pb-Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

Device	Package	Shipping [†]
NTMS10P02R2	SOIC-8	2500/Tape & Reel
NTMS10P02R2G	SOIC-8 (Pb-Free)	2500/Tape & Reel

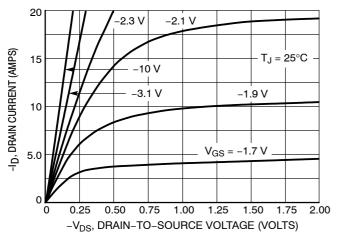
†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

1

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted) (Note 4)

Characteristic		Symbol	Min	Тур	Max	Unit
OFF CHARACTERISTICS						
Drain-to-Source Breakdown Voltage (V _{GS} = 0 Vdc, I _D = -250 μAdc)		V _{(BR)DSS}	-20	_		Vdc
Temperature Coefficient (Positive)			-	-12.1	_	mV/°C
Zero Gate Voltage Drain Current $ (V_{DS} = -20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 25^{\circ}\text{C}) $ $ (V_{DS} = -20 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, T_J = 70^{\circ}\text{C}) $		I _{DSS}	- -	- -	-1.0 -5.0	μAdc
Gate-Body Leakage Current (V _{GS} = -12 Vdc, V _{DS} = 0 Vdc)		I _{GSS}	_	-	-100	nAdc
Gate-Body Leakage Current (V _{GS} = +12 Vdc, V _{DS} = 0 Vdc)		I _{GSS}	-	-	100	nAdc
ON CHARACTERISTICS				-		•
Gate Threshold Voltage $(V_{DS} = V_{GS}, I_D = -250 \mu Adc)$ Temperature Coefficient (Negative)		V _{GS(th)}	-0.6 -	-0.88 2.8	-1.20 -	Vdc mV/°C
Static Drain-to-Source On-State F $(V_{GS} = -4.5 \text{ Vdc}, I_D = -10 \text{ Adc})$ $(V_{GS} = -2.5 \text{ Vdc}, I_D = -8.8 \text{ Adc})$	Resistance	R _{DS(on)}	1 1	0.012 0.017	0.014 0.020	Ω
Forward Transconductance (V _{DS} = -10 Vdc, I _D = -10 Adc)		9FS	-	30	-	Mhos
DYNAMIC CHARACTERISTICS						
Input Capacitance		C _{iss}	1	3100	3640	pF
Output Capacitance	$(V_{DS} = -16 \text{ Vdc}, V_{GS} = 0 \text{ Vdc}, $ f = 1.0 MHz)	C _{oss}	-	1100	1670	
Reverse Transfer Capacitance	ŕ	C _{rss}	-	475	1010	
SWITCHING CHARACTERISTICS (Notes 5 & 6)	<u> </u>		5	_	_
Turn-On Delay Time		t _{d(on)}	ı	25	35	ns
Rise Time	$(V_{DD} = -10 \text{ Vdc}, I_D = -1.0 \text{ Adc}, V_{GS} = -4.5 \text{ Vdc},$	t _r	1	40	65	
Turn-Off Delay Time	$R_{G} = 6.0 \Omega$	t _{d(off)}	-	110	190	
Fall Time		t _f	-	110	190	1
Turn-On Delay Time		t _{d(on)}	-	25	-	ns
Rise Time	$(V_{DD} = -10 \text{ Vdc}, I_D = -10 \text{ Adc},$	t _r	-	100	-	
Turn-Off Delay Time	$V_{GS} = -4.5 \text{ Vdc},$ $R_G = 6.0 \Omega)$	t _{d(off)}	=	100	_	
Fall Time		t _f	-	125	_	
Total Gate Charge	(V _{DS} = −10 Vdc,	Q _{tot}	-	48	70	nC
Gate-Source Charge	$V_{GS} = -4.5 \text{ Vdc},$	Q_{gs}	-	6.5	-	
Gate-Drain Charge	I _D = -10 Adc)	Q_{gd}	-	17	-	
BODY-DRAIN DIODE RATINGS (No	ote 5)					
Diode Forward On-Voltage	$(I_S = -2.1 \text{ Adc}, V_{GS} = 0 \text{ Vdc})$ $(I_S = -2.1 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, T_J = 125^{\circ}\text{C})$	V _{SD}	-	-0.72 -0.60	-1.2 -	Vdc
Diode Forward On-Voltage	$(I_S = -10 \text{ Adc}, V_{GS} = 0 \text{ Vdc})$ $(I_S = -10 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, T_J = 125^{\circ}\text{C})$	V _{SD}	1	-0.90 -0.75	- -	Vdc
Reverse Recovery Time			1	65	100	ns
	$(I_S = -2.1 \text{ Adc}, V_{GS} = 0 \text{ Vdc}, \\ dI_S/dt = 100 \text{ A}/\mu\text{s})$	t _a	_	25	_	
		t _b	-	40	-	
Reverse Recovery Stored Charge		Q_{RR}	-	0.075	_	μC

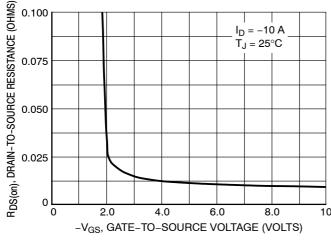
- Handling precautions to protect against electrostatic discharge is mandatory.
 Indicates Pulse Test: Pulse Width = 300 μs max, Duty Cycle = 2%.
 Switching characteristics are independent of operating junction temperature.



10 $V_{DS} \ge -10 \text{ V}$ 8.0 -ID, DRAIN CURRENT (AMPS) 6.0 25°C 4.0 T_J = -55°C 100°C 2.0 0 **L** 0.5 2.5 1.0 1.5 2.0 -VGS, GATE-TO-SOURCE VOLTAGE (VOLTS)

Figure 1. On-Region Characteristics

Figure 2. Transfer Characteristics



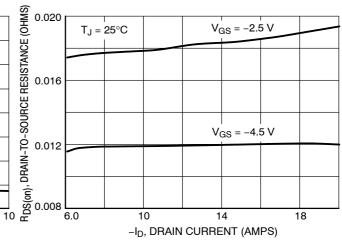
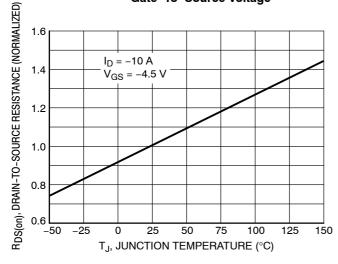


Figure 3. On-Resistance versus Gate-To-Source Voltage

Figure 4. On-Resistance versus Drain Current and Gate Voltage



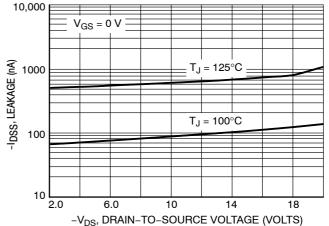
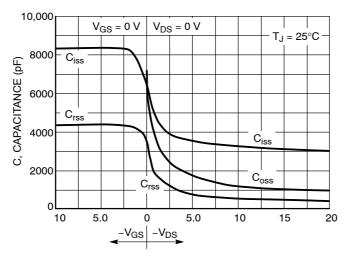


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-To-Source Leakage Current versus Voltage



GATE-TO-SOURCE OR DRAIN-TO-SOURCE VOLTAGE (VOLTS)

Figure 7. Capacitance Variation

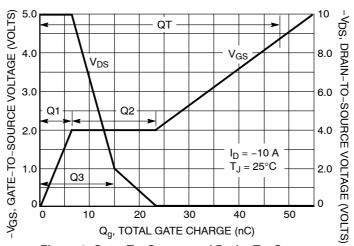


Figure 8. Gate-To-Source and Drain-To-Source Voltage versus Total Charge

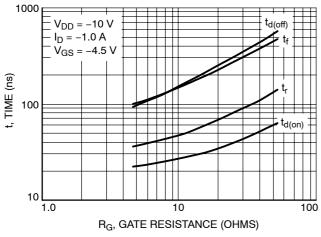


Figure 9. Resistive Switching Time Variation versus Gate Resistance

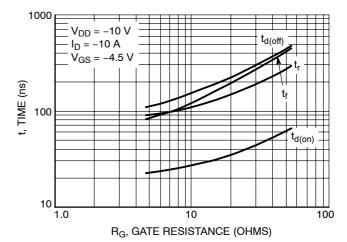


Figure 10. Resistive Switching Time Variation versus Gate Resistance

DRAIN-TO-SOURCE DIODE CHARACTERISTICS

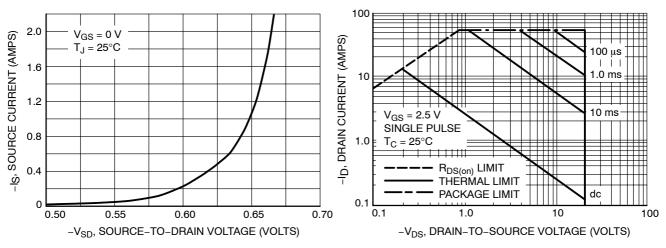


Figure 11. Diode Forward Voltage versus Current

Figure 12. Maximum Rated Forward Biased Safe Operating Area

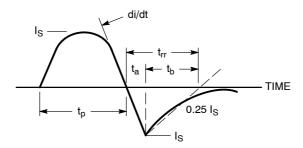


Figure 13. Diode Reverse Recovery Waveform

TYPICAL ELECTRICAL CHARACTERISTICS

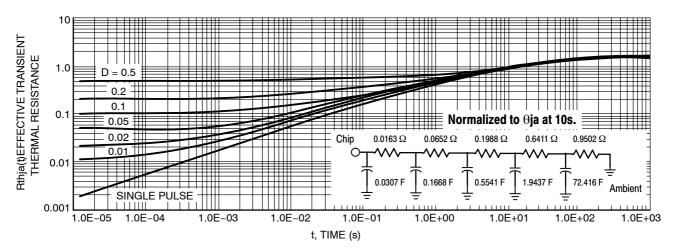
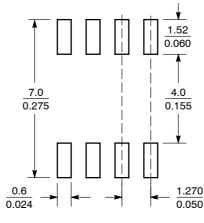


Figure 14. Thermal Response

PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07 **ISSUE AG** -X-0.25 (0.010) M Y M -Y-G C SEATING -Z-0.10 (0.004) 0.25 (0.010) M Z Y S ΧS

SOLDERING FOOTPRINT*



Mounting Techniques Reference Manual, SOLDERRM/D.

inches SCALE 6:1 *For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and

NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE
- MOLD PROTRUSION.
 MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE.
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

STYLE 12:

- PIN 1 SOURCE
 - SOURCE SOURCE
 - 3. GATE 4.
 - 5. DRAIN
 - DRAIN
 - DRAIN DRAIN

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